Search Notes

Application/Control No.		Applicant(s)/Patent under Reexamination		
10/676,258		MIYANO ET AL	•	
Examiner		Art Unit		
B. Chen		1762		

SEARCHED					
Subclass	Date	Examiner			
595 582 586	9/15/2005	вс			
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	595 582 586	Subclass Date  595 582 586  9/15/2005			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
west	9/15/2005	ВС		